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PATENT APPLICATION  
Docket No.: 8750-017  
Client Ref. No.: SPX200110-0010US

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re application of: Sang-Eun LEE and Jae-Sung HAN

Serial No.: 10/068,152 Examiner: Hollington, Jermele M.

Filed: February 6, 2002 Group Art Unit: 2829

Confirmation No.: 7500

For: METHOD OF IDENTIFYING AND ANALYZING  
SEMICONDUCTOR CHIP DEFECTS

Mail Stop Amendment  
Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

**AMENDMENT AFTER ALLOWANCE UNDER 37 CFR § 312**

Responsive to the Notice of Allowance dated March 24, 2005, please amend the application as follows.

Amendments to the Claims begin on page 2 of this paper.

Remarks/Arguments begin on page 4 of this paper.

*O.K. to  
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9-H  
11/17/05*